

L Number	Hits	Search Text	DB	Time stamp
1	4732	(250/306,307,311,442.11).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 15:45
2	7	(((((imag\$4 with (sample or wafer or specimen or semiconductor)) and (stor\$4 near4 (data or information) with (area or region))) and (control\$4 with position\$3 with (sample or wafer or substrate or semiconductor))) and (locat\$4 near2 defect\$4)) and (scale or scaling)) and ((250/306,307,311,442.11).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 15:47
3	36765	inspect\$5 near4 (sample or wafer or semiconductor or substrate or defect or anomaly)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 15:51
4	11	"6292582" and (scale or scaling)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 15:54
5	615	(referenc\$4 near1 image) and (inspect\$4 near4 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 15:55
6	157	((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 15:57
7	18	((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and (scale near1 (value or factor\$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:08
8	10	(((((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and (scale near1 (value or factor\$3))) and (locat\$5 near3 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:12
9	5	(((((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and (scale near1 (value or factor\$3))) and (locat\$5 near3 defect)) and (magnif\$5 with imag\$4 with defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:12
10	5	(((((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and (scale near1 (value or factor\$3))) and (locat\$5 near3 defect)) and (magnif\$5 with imag\$4 with defect)) and display\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:13
12	20	((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and ((scale or reduc\$4 or magnif\$5) near1 (value or factor\$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:09
13	1	(((((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and ((scale or reduc\$4 or magnif\$5) near1 (value or factor\$3))) and ((scale or reduc\$4 or magnif\$5) near1 second)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:10

14	0	(((((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and ((scale or reduc\$4 or magnif\$5) near1 (value or factor\$3))) and ((scale or reduc\$4 or magnif\$5) near1 second)) and (locat\$5 near3 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:11
11	18	((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and (scale near1 (value or factor\$3 or coefficient))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:12
15	10	(((((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and (scale near1 (value or factor\$3 or coefficient))) and (locat\$5 near3 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:12
16	8	(((((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and (scale near1 (value or factor\$3 or coefficient))) and (locat\$5 near3 defect)) and (magnif\$5 with imag\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:13
17	8	(((((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and (scale near1 (value or factor\$3 or coefficient))) and (locat\$5 near3 defect)) and (magnif\$5 with imag\$4)) and display\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:34
18	0	((((((referenc\$4 near1 image) and (inspect\$4 near4 defect)) and ((position\$3 or mov\$4) with view\$3)) and (scale near1 (value or factor\$3 or coefficient))) and (locat\$5 near3 defect)) and (magnif\$5 with imag\$4)) and display\$4) and ((250/306,307,311,442.11).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:34